


Search Notes 	Application/Control No. 10551039	Applicant(s)/Patent Under Reexamination FUJITA ET AL.
	Examiner NIKHIL SRIRAMAN	Art Unit 3664

SEARCHED			
Class	Subclass	Date	Examiner
700	245, 248, 249, 250, 253	12/20/2008	NS

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Marc McDieunel	12/20/2008	
Assignee search on East, Inventor search on eDan		
NPL, including IEEE databases searched (see attached history)		
Reviewed submitted IDS references	7/12/2009	
Updated search in light of claim amendments; consulted with Examiner Jorge Peche and Examiner Kyung Kim on search strategy on claim interpretation	12/19/2009	
Consulted with Examiner Lin Olsen on apparatus claim construction in light of removal of "means plus function" language in Applicant's amendment	6/25/2010	
updated search, see attached EAST Search history	3/8/2011	JE

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/J. E./ Examiner.Art Unit 3664	
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